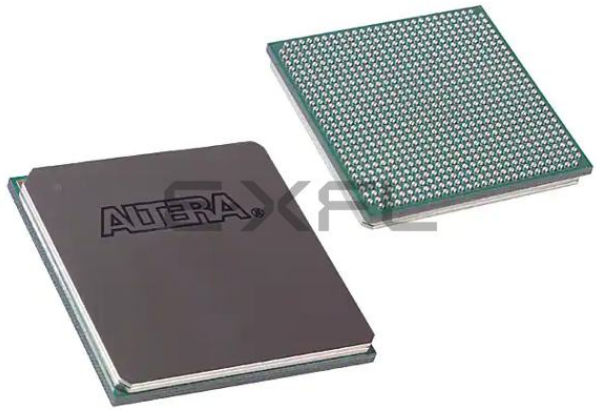

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	3022
Number of Logic Elements/Cells	60440
Total RAM Bits	2544192
Number of I/O	364
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	780-BBGA
Supplier Device Package	780-FBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2sgx60cf780c5

Table 1–3. Stratix II GX FineLine BGA Package Sizes			
Dimension	**780 Pins**	**1,152 Pins**	**1,508 Pins**
Pitch (mm)	1.00	1.00	1.00
Area (mm^2)	841	1,225	1,600
Length width (mm × mm)	29 × 29	35 × 35	40 × 40

Referenced Document

This chapter references the following document:

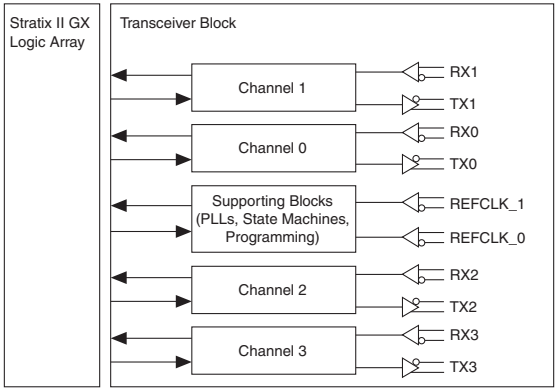
- *Stratix II GX Architecture* chapter in volume 1 of the *Stratix II GX Device Handbook*

Document Revision History

Table 1–4 shows the revision history for this chapter.

Table 1–4. Document Revision History		
Date and Document Version	**Changes Made**	**Summary of Changes**
October 2007, v1.6	Updated "Features" section.	
	Minor text edits.	
August 2007, v1.5	Added "Referenced Documents" section.	
	Minor text edits.	
February 2007, v1.4	• Changed 622 Mbps to 600 Mbps on page 1-2 and Table 1–1. • Deleted "DC coupling" from the Transceiver Block Features list. • Changed 4 to 6 in the PLLs row (columns 3 and 4) of Table 1–1.	
	Added the "Document Revision History" section to this chapter.	Added support information for the Stratix II GX device.
June 2006, v1.3	• Updated Table 1–2.	
April 2006, v1.2	• Updated Table 1–1. • Updated Table 1–2.	Updated numbers for receiver channels and user I/O pin counts in Table 1–2.
February 2006, v1.1	• Updated Table 1–1.	
October 2005 v1.0	Added chapter to the *Stratix II GX Device Handbook*.	

Figure 2–2. Elements of the Transceiver Block



Each Stratix II GX transceiver channel consists of a transmitter and receiver. The transceivers are grouped in four and share PLL resources. Each transmitter has access to one of two PLLs. The transmitter contains the following:

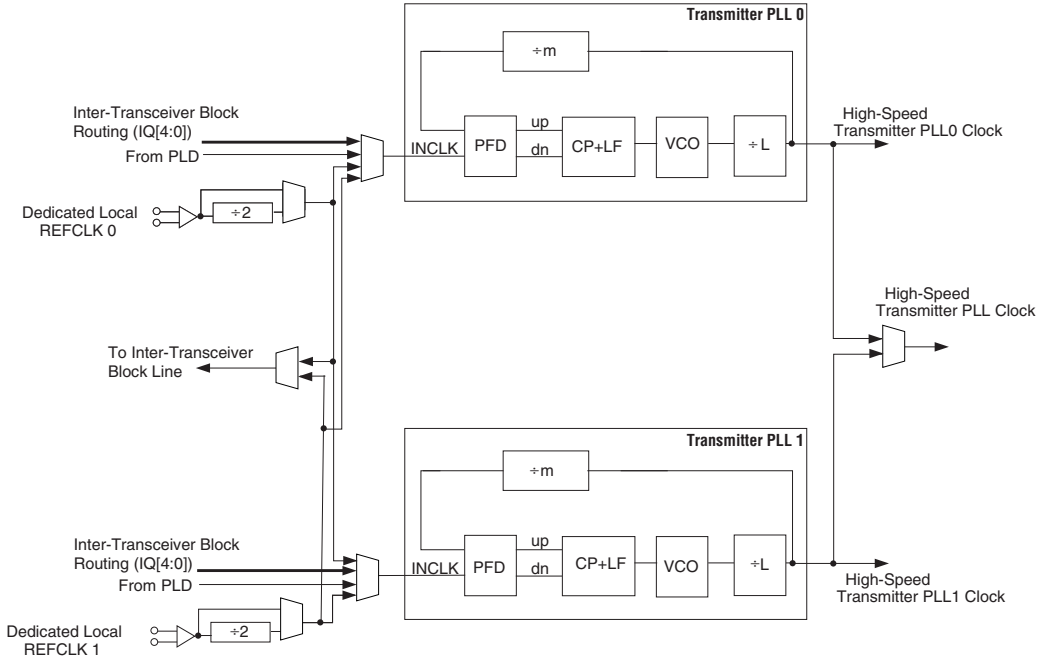
- Transmitter phase compensation first-in first-out (FIFO) buffer
- Byte serializer (optional)
- 8B/10B encoder (optional)
- Serializer (parallel-to-serial converter)
- Transmitter differential output buffer

The receiver contains the following:

- Receiver differential input buffer
- Receiver lock detector and run length checker
- Clock recovery unit (CRU)
- Deserializer
- Pattern detector
- Word aligner
- Lane deskew
- Rate matcher (optional)
- 8B/10B decoder (optional)
- Byte deserializer (optional)
- Byte ordering
- Receiver phase compensation FIFO buffer

Designers can preset Stratix II GX transceiver functions using the Quartus® II software. In addition, pre-emphasis, equalization, and differential output voltage (V_{OD}) are dynamically programmable. Each Stratix II GX transceiver channel supports various loopback modes and is

Figure 2–4. Transmitter PLL Block Note (1)



Note to Figure 2–4:
(1) The global clock line must be driven by an input pin.

The transmitter PLLs support data rates up to 6.375 Gbps. The input clock frequency is limited to 622.08 MHz. An optional `pll_locked` port is available to indicate whether the transmitter PLL is locked to the reference clock. Both transmitter PLLs have a programmable loop bandwidth parameter that can be set to low, medium, or high. The loop bandwidth parameter can be statically set in the Quartus II software.

Table 2–2 lists the adjustable parameters in the transmitter PLL.

Table 2–2. Transmitter PLL Specifications

Parameter	Specifications
Input reference frequency range	50 MHz to 622.08 MHz
Data rate support	600 Mbps to 6.375 Gbps
Multiplication factor (W)	1, 4, 5, 8, 10, 16, 20, 25
Bandwidth	Low, medium, or high

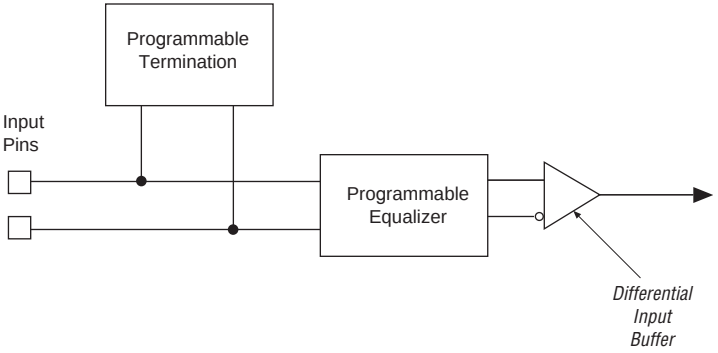
- Lane deskew
- Rate matcher
- 8B/10B decoder
- Byte deserializer
- Byte ordering
- Receiver phase compensation FIFO buffer

Receiver Input Buffer

The Stratix II GX receiver input buffer supports the 1.2-V and 1.5-V PCML I/O standard at rates up to 6.375 Gbps. The common mode voltage of the receiver input buffer is programmable between 0.85 V and 1.2 V. You must select the 0.85 V common mode voltage for AC- and DC-coupled PCML links and the 1.2 V common mode voltage for DC-coupled LVDS links.

The receiver has programmable on-chip 100-, 120-, or 150-Ω differential termination for different protocols, as shown in Figure 2–12. The receiver's internal termination can be disabled if external terminations and biasing are provided. The receiver and transmitter differential termination resistances can be set independently of each other.

Figure 2–12. Receiver Input Buffer



Programmable Termination

The programmable termination can be statically set in the Quartus II software. Figure 2–13 shows the setup for programmable receiver termination. The termination can be disabled if external termination is provided.

The CRU has a built-in switchover circuit to select whether the PLL VCO is aligned by the reference clock or the data. The optional port rx_freqlocked monitors when the CRU is in locked-to-data mode.

In the automatic mode, the CRU PLL must be within the prescribed PPM frequency threshold setting of the CRU reference clock for the CRU to switch from locked-to-reference to locked-to-data mode.

The automatic switchover circuit can be overridden by using the optional ports rx_locktorefclk and rx_locktodata. Table 2–6 shows the possible combinations of these two signals.

Table 2–6. Receiver Lock Combinations

rx_locktodata	rx_locktorefclk	VCO (Lock to Mode)
0	0	Auto
0	1	Reference clock
1	x	Data

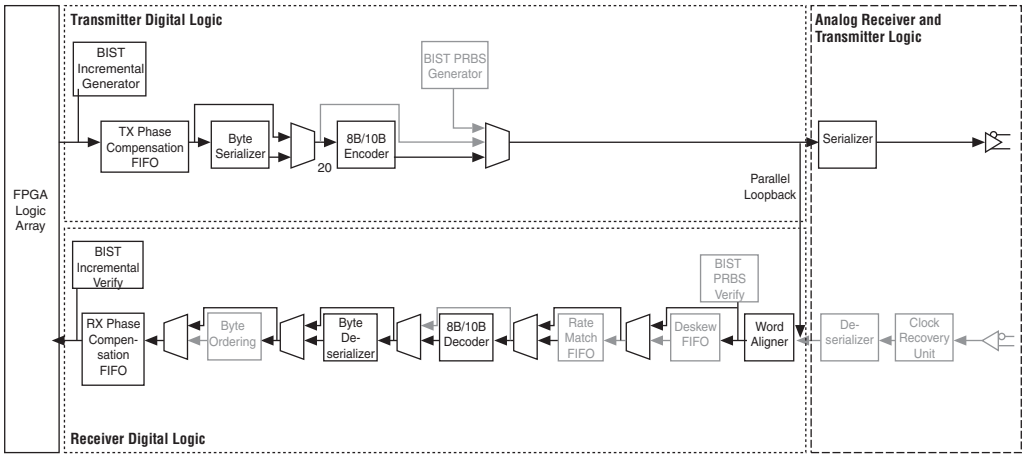
If the rx_locktorefclk and rx_locktodata ports are not used, the default is auto mode.

Deserializer (Serial-to-Parallel Converter)

The deserializer converts a serial bitstream into 8, 10, 16, or 20 bits of parallel data. The deserializer receives the LSB first. Figure 2–17 shows the deserializer.

Figure 2–25 shows the data path in parallel loopback mode.

Figure 2–25. Stratix II GX Block in Parallel Loopback Mode

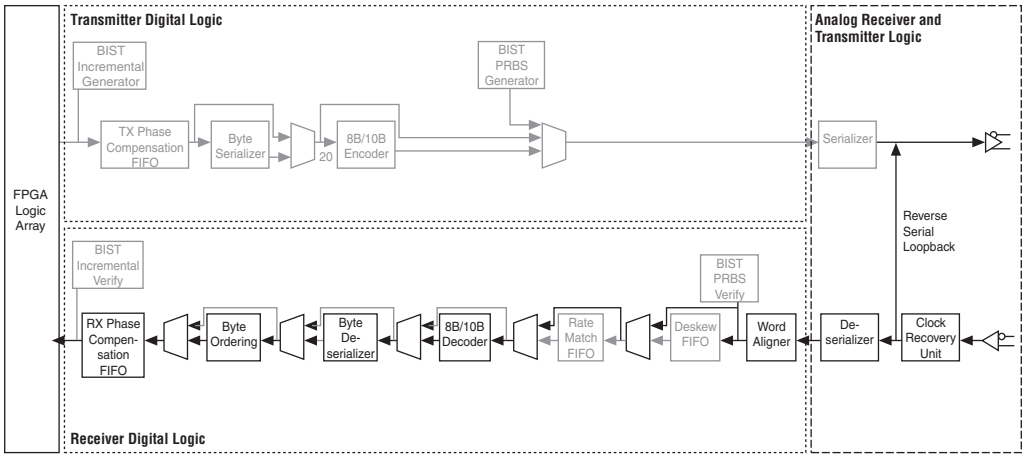


Reverse Serial Loopback

The reverse serial loopback mode uses the analog portion of the transceiver. An external source (pattern generator or transceiver) generates the source data. The high-speed serial source data arrives at the high-speed differential receiver input buffer, passes through the CRU unit, and the retimed serial data is looped back and transmitted though the high-speed differential transmitter output buffer.

Figure 2–26 shows the data path in reverse serial loopback mode.

Figure 2–26. Stratix II GX Block in Reverse Serial Loopback Mode



Reverse Serial Pre-CDR Loopback

The reverse serial pre-CDR loopback mode uses the analog portion of the transceiver. An external source (pattern generator or transceiver) generates the source data. The high-speed serial source data arrives at the high-speed differential receiver input buffer, loops back before the CRU unit, and is transmitted though the high-speed differential transmitter output buffer. It is for test or verification use only to verify the signal being received after the gain and equalization improvements of the input buffer. The signal at the output is not exactly what is received since the signal goes through the output buffer and the VOD is changed to the VOD setting level. The pre-emphasis settings have no effect.

Table 2–13. Available Clocking Connections for Transceivers in 2SGX60E

Region	Clock Resource		Transceiver		
	Global Clock	Regional Clock	Bank 13 8 Clock I/O	Bank 14 8 Clock I/O	Bank 15 8 Clock I/O
Region0 8 LRIO clock	✓	RCLK 20-27	✓		
Region1 8 LRIO clock	✓	RCLK 20-27	✓	✓	
Region2 8 LRIO clock	✓	RCLK 12-19		✓	✓
Region3 8 LRIO clock	✓	RCLK 12-19			✓

Table 2–14. Available Clocking Connections for Transceivers in 2SGX90F

Region	Clock Resource		Transceiver			
	Global Clock	Regional Clock	Bank 13 8 Clock I/O	Bank 14 8 Clock I/O	Bank 15 8 clock I/O	Bank 16 8 Clock I/O
Region0 8 LRIO clock	✓	RCLK 20-27	✓			
Region1 8 LRIO clock	✓	RCLK 20-27		✓		
Region2 8 LRIO clock	✓	RCLK 12-19			✓	
Region3 8 LRIO clock	✓	RCLK 12-19				✓

The RAM blocks in Stratix II GX devices have local interconnects to allow ALMs and interconnects to drive into RAM blocks. The M512 RAM block local interconnect is driven by the R4, C4, and direct link interconnects from adjacent LABs. The M512 RAM blocks can communicate with LABs on either the left or right side through these row interconnects or with LAB columns on the left or right side with the column interconnects. The M512 RAM block has up to 16 direct link input connections from the left adjacent LABs and another 16 from the right adjacent LAB. M512 RAM outputs can also connect to left and right LABs through direct link interconnect. The M512 RAM block has equal opportunity for access and performance to and from LABs on either its left or right side. Figure 2–50 shows the M512 RAM block to logic array interface.

Figure 2–50. M512 RAM Block LAB Row Interface

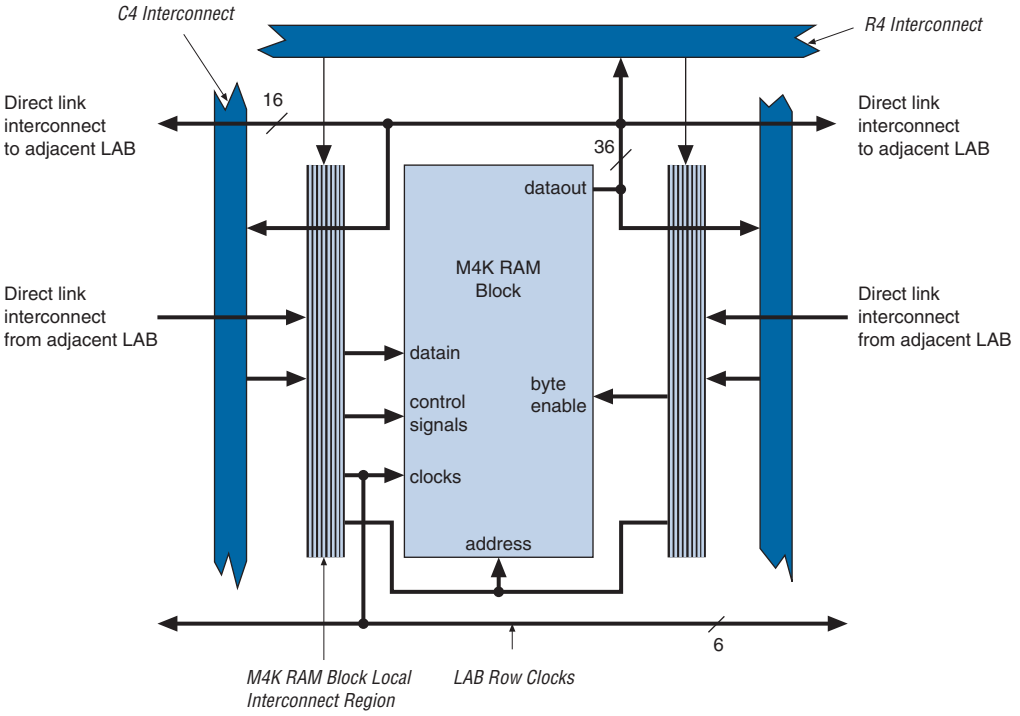
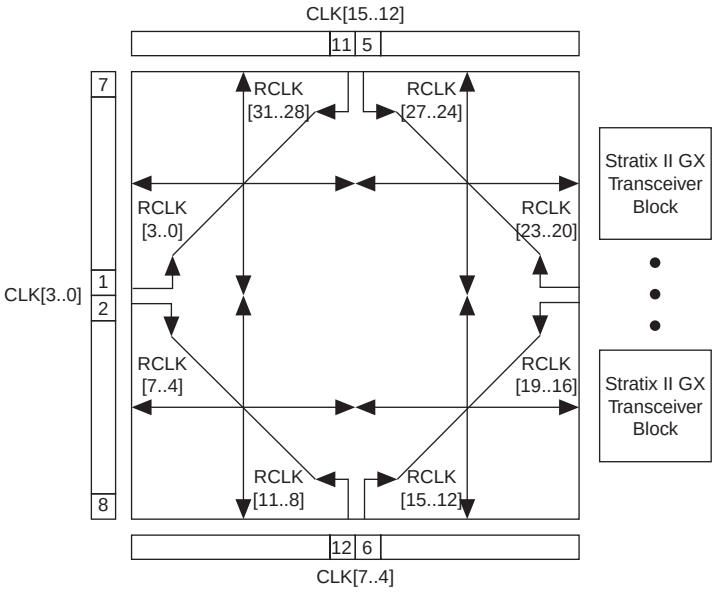


Figure 2–62. Regional Clocks



Dual-Regional Clock Network

A single source (CLK pin or PLL output) can generate a dual-regional clock by driving two regional clock network lines in adjacent quadrants (one from each quadrant), which allows logic that spans multiple quadrants to utilize the same low skew clock. The routing of this clock signal on an entire side has approximately the same speed but slightly higher clock skew when compared with a clock signal that drives a single quadrant. Internal logic-array routing can also drive a dual-regional clock. Clock pins and enhanced PLL outputs on the top and bottom can drive horizontal dual-regional clocks. Clock pins and fast PLL outputs on the left and right can drive vertical dual-regional clocks, as shown in Figure 2–63. Corner PLLs cannot drive dual-regional clocks.

For more information on tolerance specifications for differential on-chip termination, refer to the *DC & Switching Characteristics* chapter in volume 1 of the *Stratix II GX Device Handbook*.

On-Chip Series Termination without Calibration

Stratix II GX devices support driver impedance matching to provide the I/O driver with controlled output impedance that closely matches the impedance of the transmission line. As a result, reflections can be significantly reduced. Stratix II GX devices support on-chip series termination for single-ended I/O standards with typical R_S values of 25 and 50 Ω. Once matching impedance is selected, current drive strength is no longer selectable. Table 2–34 shows the list of output standards that support on-chip series termination without calibration.

For more information about series on-chip termination supported by Stratix II GX devices, refer to the *Selectable I/O Standards in Stratix II & Stratix II GX Devices* chapter in volume 2 of the *Stratix II GX Device Handbook*.

For more information about tolerance specifications for on-chip termination without calibration, refer to the *DC & Switching Characteristics* chapter in volume 1 of the *Stratix II GX Device Handbook*.

On-Chip Series Termination with Calibration

Stratix II GX devices support on-chip series termination with calibration in column I/O pins in top and bottom banks. There is one calibration circuit for the top I/O banks and one circuit for the bottom I/O banks. Each on-chip series termination calibration circuit compares the total impedance of each I/O buffer to the external 25-Ω or 50-Ω resistors connected to the `RUP` and `RDN` pins, and dynamically enables or disables the transistors until they match. Calibration occurs at the end of device configuration. Once the calibration circuit finds the correct impedance, it powers down and stops changing the characteristics of the drivers.

For more information about series on-chip termination supported by Stratix II GX devices, refer to the *Selectable I/O Standards in Stratix II & Stratix II GX Devices* chapter in volume 2 of the *Stratix II GX Device Handbook*.

For more information about tolerance specifications for on-chip termination with calibration, refer to the *DC & Switching Characteristics* chapter in volume 1 of the *Stratix II GX Device Handbook*.

Table 3–1. Stratix II GX JTAG Instructions

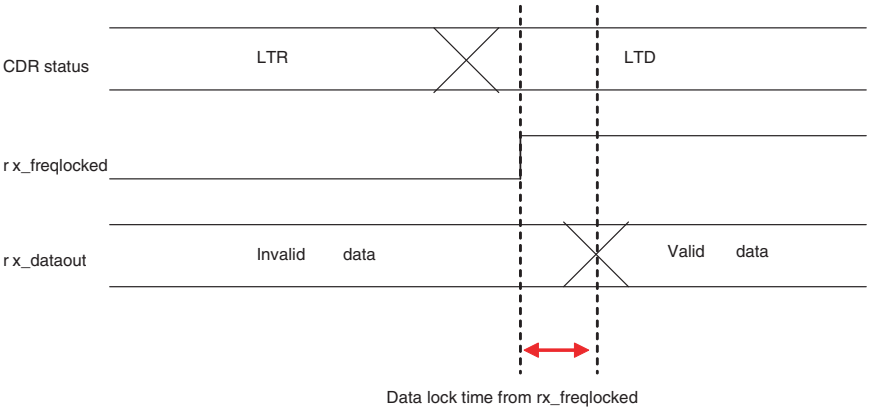
JTAG Instruction	Instruction Code	Description
SAMPLE/PRELOAD	00 0000 0101	Allows a snapshot of signals at the device pins to be captured and examined during normal device operation and permits an initial data pattern to be output at the device pins. Also used by the SignalTap II embedded logic analyzer.
EXTEST *(1)*	00 0000 1111	Allows the external circuitry and board-level interconnects to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
BYPASS	11 1111 1111	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation.
USERCODE	00 0000 0111	Selects the 32-bit USERCODE register and places it between the TDI and TDO pins, allowing the USERCODE to be serially shifted out of TDO.
IDCODE	00 0000 0110	Selects the IDCODE register and places it between TDI and TDO, allowing the IDCODE to be serially shifted out of TDO.
HIGHZ *(1)*	00 0000 1011	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation, while tri-stating all of the I/O pins.
CLAMP *(1)*	00 0000 1010	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation while holding the I/O pins to a state defined by the data in the boundary-scan register.
ICR instructions		Used when configuring a Stratix II GX device via the JTAG port with a USB-Blaster™, MasterBlaster™, ByteBlasterMV™, or ByteBlaster II download cable, or when using a **.jam** or **.jbc** via an embedded processor or JRunner.
PULSE_NCONFIG	00 0000 0001	Emulates pulsing the nCONFIG pin low to trigger reconfiguration even though the physical pin is unaffected.
CONFIG_IO *(2)*	00 0000 1101	Allows configuration of I/O standards through the JTAG chain for JTAG testing. Can be executed before, during, or after configuration. Stops configuration if executed during configuration. Once issued, the CONFIG_IO instruction holds nSTATUS low to reset the configuration device. nSTATUS is held low until the IOE configuration register is loaded and the TAP controller state machine transitions to the UPDATE_DR state.
SignalTap II instructions		Monitors internal device operation with the SignalTap II embedded logic analyzer.

Notes to Table 3–1:

(1) Bus hold and weak pull-up resistor features override the high-impedance state of HIGHZ, CLAMP, and EXTEST.

(2) For more information on using the CONFIG_IO instruction, refer to the *MorphIO: An I/O Reconfiguration Solution for Altera Devices White Paper.*

Figure 4–2. Lock Time Parameters for Automatic Mode



Figures 4–3 and 4–4 show differential receiver input and transmitter output waveforms, respectively.

Figure 4–3. Receiver Input Waveform

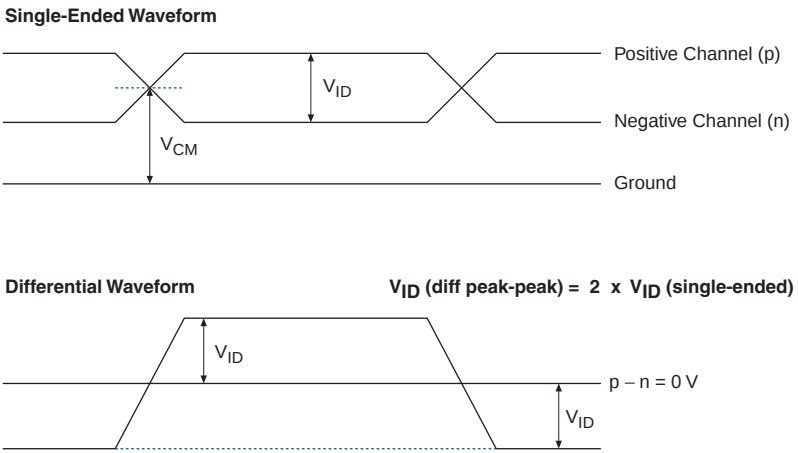


Table 4–19. Stratix II GX Transceiver Block AC Specification Notes (1), (2), (3) (Part 4 of 19)

Symbol/ Description	Conditions	-3 Speed Commercial Speed Grade			-4 Speed Commercial and Industrial Speed Grade			-5 Speed Commercial Speed Grade			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Sinusoidal jitter FC-1	Fc/25000	> 1.5			> 1.5			> 1.5			UI
	Fc/1667	> 0.1			> 0.1			> 0.1			UI
Deterministic jitter FC-2	Pattern = CJTPAT No Equalization DC Gain = 0 dB	> 0.33			> 0.33			> 0.33			UI
Random jitter FC-2	Pattern = CJTPAT No Equalization DC Gain = 0 dB	> 0.29			> 0.29			> 0.29			UI
Sinusoidal jitter FC-2	Fc/25000	> 1.5			> 1.5			> 1.5			UI
	Fc/1667	> 0.1			> 0.1			> 0.1			UI
Deterministic jitter FC-4	Pattern = CJTPAT No Equalization DC Gain = 0 dB	> 0.33			> 0.33			> 0.33			UI
Random jitter FC-4	Pattern = CJTPAT No Equalization DC Gain = 0 dB	> 0.29			> 0.29			> 0.29			UI
Sinusoidal jitter FC-4	Fc/25000	> 1.5			> 1.5			> 1.5			UI
	Fc/1667	> 0.1			> 0.1			> 0.1			UI
XAUI Transmit Jitter Generation *(9)*											
Total jitter at 3.125 Gbps	REFCLK = 156.25 MHz Pattern = CJPAT V_{OD} = 1200 mV No Pre-emphasis	-	-	0.3	-	-	0.3	-	-	0.3	UI
Deterministic jitter at 3.125 Gbps	REFCLK = 156.25 MHz Pattern = CJPAT V_{OD} = 1200 mV No Pre-emphasis	-	-	0.17	-	-	0.17	-	-	0.17	UI
XAUI Receiver Jitter Tolerance *(9)*											
Total jitter	Pattern = CJPAT No Equalization DC Gain = 3 dB	> 0.65			> 0.65			> 0.65			UI
Deterministic jitter	Pattern = CJPAT No Equalization DC Gain = 3 dB	> 0.37			> 0.37			> 0.37			UI

Table 4–19. Stratix II GX Transceiver Block AC Specification Notes (1), (2), (3) (Part 7 of 19)

Symbol/ Description	Conditions	-3 Speed Commercial Speed Grade			-4 Speed Commercial and Industrial Speed Grade			-5 Speed Commercial Speed Grade			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Sinusoidal Jitter Tolerance (peak-to-peak)	Jitter Frequency = 22.1 KHz Data Rate = 1.25, 2.5, 3.125 Gbps REFCLK = 125 MHz Pattern = CJPAT Equalizer Setting = 0 for 1.25 Gbps Equalizer Setting = 6 for 2.5 Gbps Equalizer Setting = 6 for 3.125 Gbps		> 8.5			> 8.5			> 8.5		UI
	Jitter Frequency = 1.875 MHz Data Rate = 1.25, 2.5, 3.125 Gbps REFCLK = 125 MHz Pattern = CJPAT Equalizer Setting = 0 for 1.25 Gbps Equalizer Setting = 6 for 2.5 Gbps Equalizer Setting = 6 for 3.125 Gbps		> 0.1			> 0.1			> 0.1		UI
	Jitter Frequency = 20 MHz Data Rate = 1.25, 2.5, 3.125 Gbps REFCLK = 125 MHz Pattern = CJPAT Equalizer Setting = 0 for 1.25 Gbps Equalizer Setting = 6 for 2.5 Gbps Equalizer Setting = 6 for 3.125 Gbps		> 0.1			> 0.1			> 0.1		UI

Table 4–41. 1.2-V HSTL Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{OH}	High-level output voltage	I_{OH} = 8 mA	V_{REF} + 0.15		V_{CCIO} + 0.15	V
V_{OL}	Low-level output voltage	I_{OH} = –8 mA	–0.15		V_{REF} – 0.15	V

Table 4–42. 1.5-V HSTL Class I Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		1.425	1.5	1.575	V
V_{REF}	Input reference voltage		0.713	0.75	0.788	V
V_{TT}	Termination voltage		0.713	0.75	0.788	V
V_{IH} (DC)	DC high-level input voltage		V_{REF} + 0.1			V
V_{IL} (DC)	DC low-level input voltage		–0.3		V_{REF} – 0.1	V
V_{IH} (AC)	AC high-level input voltage		V_{REF} + 0.2			V
V_{IL} (AC)	AC low-level input voltage				V_{REF} – 0.2	V
V_{OH}	High-level output voltage	I_{OH} = 8 mA *(1)*	V_{CCIO} – 0.4			V
V_{OL}	Low-level output voltage	I_{OH} = –8 mA *(1)*			0.4	V

Note to Table 4–42:

(1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II GX Architecture* chapter in volume 1 of the *Stratix II GX Device Handbook*.

Table 4–43. 1.5-V HSTL Class II Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		1.425	1.50	1.575	V
V_{REF}	Input reference voltage		0.713	0.75	0.788	V
V_{TT}	Termination voltage		0.713	0.75	0.788	V
V_{IH} (DC)	DC high-level input voltage		V_{REF} + 0.1			V
V_{IL} (DC)	DC low-level input voltage		–0.3		V_{REF} – 0.1	V
V_{IH} (AC)	AC high-level input voltage		V_{REF} + 0.2			V
V_{IL} (AC)	AC low-level input voltage				V_{REF} – 0.2	V
V_{OH}	High-level output voltage	I_{OH} = 16 mA *(1)*	V_{CCIO} – 0.4			V
V_{OL}	Low-level output voltage	I_{OH} = –16 mA *(1)*			0.4	V

Note to Table 4–43:

(1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II GX Architecture* chapter in volume 1 of the *Stratix II GX Device Handbook*.

Power Consumption

Altera offers two ways to calculate power for a design: the Excel-based PowerPlay early power estimator power calculator and the Quartus® II PowerPlay power analyzer feature.

The interactive Excel-based PowerPlay early power estimator is typically used prior to designing the FPGA in order to get an estimate of device power. The Quartus II PowerPlay power analyzer provides better quality estimates based on the specifics of the design after place-and-route is complete. The power analyzer can apply a combination of user-entered, simulation-derived and estimated signal activities which, combined with detailed circuit models, can yield very accurate power estimates.

In both cases, these calculations should only be used as an estimation of power, not as a specification.

For more information on PowerPlay tools, refer to the *PowerPlay Early Power Estimators (EPE) and Power Analyzer,* the *Quartus II PowerPlay Analysis and Optimization Technology*, and the *PowerPlay Power Analyzer* chapter in volume 3 of the *Quartus II Handbook*. The PowerPlay early power estimators are available on the Altera web site at **www.altera. com**.

See Table 4–23 on page 42 for typical I_{CC} standby specifications.

Timing Model

The DirectDrive technology and MultiTrack interconnect ensure predictable performance, accurate simulation, and accurate timing analysis across all Stratix II GX device densities and speed grades. This section describes and specifies the performance, internal, external, and PLL timing specifications.

All specifications are representative of worst-case supply voltage and junction temperature conditions.

Preliminary and Final Timing

Timing models can have either preliminary or final status. The Quartus II software issues an informational message during the design compilation if the timing models are preliminary. Table 4–52 shows the status of the Stratix II GX device timing models.

Preliminary status means the timing model is subject to change. Initially, timing numbers are created using simulation results, process data, and other known parameters. These tests are used to make the preliminary numbers as close to the actual timing parameters as possible.

Table 4–86. Stratix II GX I/O Output Delay for Column Pins (Part 1 of 7)								
I/O Standard	Drive Strength	Parameter	Fast Corner Industrial/ Commercial	-3 Speed Grade *(3)*	-3 Speed Grade *(4)*	-4 Speed Grade	-5 Speed Grade	Unit
LVTTL	4 mA	t_{OP}	1236	2351	2467	2624	2820	ps
		t_{DIP}	1258	2417	2537	2698	2910	ps
	8 mA	t_{OP}	1091	2036	2136	2272	2448	ps
		t_{DIP}	1113	2102	2206	2346	2538	ps
	12 mA	t_{OP}	1024	2036	2136	2272	2448	ps
		t_{DIP}	1046	2102	2206	2346	2538	ps
	16 mA	t_{OP}	998	1893	1986	2112	2279	ps
		t_{DIP}	1020	1959	2056	2186	2369	ps
	20 mA	t_{OP}	976	1787	1875	1994	2154	ps
		t_{DIP}	998	1853	1945	2068	2244	ps
	24 mA *(1)*	t_{OP}	969	1788	1876	1995	2156	ps
		t_{DIP}	991	1854	1946	2069	2246	ps
LVCMOS	4 mA	t_{OP}	1091	2036	2136	2272	2448	ps
		t_{DIP}	1113	2102	2206	2346	2538	ps
	8 mA	t_{OP}	999	1786	1874	1993	2153	ps
		t_{DIP}	1021	1852	1944	2067	2243	ps
	12 mA	t_{OP}	971	1720	1805	1919	2075	ps
		t_{DIP}	993	1786	1875	1993	2165	ps
	16 mA	t_{OP}	978	1693	1776	1889	2043	ps
		t_{DIP}	1000	1759	1846	1963	2133	ps
	20 mA	t_{OP}	965	1677	1759	1871	2025	ps
		t_{DIP}	987	1743	1829	1945	2115	ps
	24 mA *(1)*	t_{OP}	954	1659	1741	1851	2003	ps
		t_{DIP}	976	1725	1811	1925	2093	ps

Table 4–88. Stratix II GX Maximum Input Clock Rate for Column I/O Pins (Part 2 of 2)				
I/O Standard	-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
Differential SSTL-18 Class I I	500	500	500	MHz
1.8-V differential HSTL Class I	500	500	500	MHz
1.8-V differential HSTL Class II	500	500	500	MHz
1.5-V differential HSTL Class I	500	500	500	MHz
1.5-V differential HSTL Class I I	500	500	500	MHz
1.2-V HSTL	280	250	250	MHz
1.2-V differential HSTL	280	250	250	MHz

Table 4–89 shows the maximum input clock toggle rates for Stratix II GX device row pins.

Table 4–89. Stratix II GX Maximum Input Clock Rate for Row I/O Pins (Part 1 of 2)				
I/O Standard	-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
LVTTL	500	500	450	MHz
2.5 V	500	500	450	MHz
1.8 V	500	500	450	MHz
1.5 V	500	500	450	MHz
LVCMOS	500	500	450	MHz
SSTL-2 Class I	500	500	500	MHz
SSTL-2 Class II	500	500	500	MHz
SSTL-18 Class I	500	500	500	MHz
SSTL-18 Class II	500	500	500	MHz
1.5-V HSTL Class I	500	500	500	MHz
1.5-V HSTL Class II	500	500	500	MHz
1.8-V HSTL Class I	500	500	500	MHz
1.8-V HSTL Class II	500	500	500	MHz
PCI	500	500	425	MHz
PCI-X	500	500	425	MHz
Differential SSTL-2 Class I	500	500	500	MHz

Table 4–91. Stratix II GX Maximum Output Clock Rate for Column Pins (Part 2 of 3)					
I/O Standard	**Drive Strength**	**-3 Speed Grade**	**-4 Speed Grade**	**-5 Speed Grade**	**Unit**
SSTL-18 Class I	4 mA	200	150	150	MHz
	6 mA	350	250	200	MHz
	8 mA	450	300	300	MHz
	10 mA	500	400	400	MHz
	12 mA *(1)*	700	550	400	MHz
SSTL-18 Class II	8 mA	200	200	150	MHz
	16 mA	400	350	350	MHz
	18 mA	450	400	400	MHz
	20 mA *(1)*	550	500	450	MHz
1.8-V HSTL Class I	4 mA	300	300	300	MHz
	6 mA	500	450	450	MHz
	8 mA	650	600	600	MHz
	10 mA	700	650	600	MHz
	12 mA *(1)*	700	700	650	MHz
1.8-V HSTL Class II	16 mA	500	500	450	MHz
	18 mA	550	500	500	MHz
	20 mA *(1)*	650	550	550	MHz
1.5-V HSTL Class I	4 mA	350	300	300	MHz
	6 mA	500	500	450	MHz
	8 mA	700	650	600	MHz
	10 mA	700	700	650	MHz
	12 mA *(1)*	700	700	700	MHz
1.5-V HSTL Class II	16 mA	600	600	550	MHz
	18 mA	650	600	600	MHz
	20 mA *(1)*	700	650	600	MHz
PCI	-	1000	790	670	MHz
PCI-X	-	1000	790	670	MHz
Differential SSTL-2 Class I	8 mA	400	300	300	MHz
	12 mA	400	400	350	MHz
Differential SSTL-2 Class II	16 mA	350	350	300	MHz
	20 mA	400	350	350	MHz
	24 mA	400	400	350	MHz